

SSF8205

Main Product Characteristics:

V _{DSS}	20V
R _{DS} (on)	20mohm(typ.)
I _D	4A

SOT23-6

Marking and pin Assignment

Schematic diagram

Features and Benefits:

- Advanced trench MOSFET process technology
- Special designed for buttery protection, load switching and general power management
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in buttery protection, power switching application and a wide variety of other applications

Absolute max Rating:

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	20	V
Gate-Source Voltage	Vgs	±10	V
Drain Current Continuous@ Current Duland (Note 1)	I _D	4	А
Drain Current-Continuous@ Current-Pulsed (Note 1)	I _{DM}	25	А
Maximum Power Dissipation	P _D	1.25	W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	°C

Thermal Resistance

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	100	°C /W
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Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Parameter	Symbol	Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA				V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V,V _{GS} =0V			1	μA
Gate-Body Leakage Current	I _{GSS}	$V_{GS}=\pm 10V, V_{DS}=0V$			±100	nA
ON CHARACTERISTICS (Note 3)			•			
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_D=250\mu A$	0.5	0.8	1.2	V
Drain Source On State Desistance	D	V _{GS} =4V, I _D =4A		20	30	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =2.5V, I _D =3A		25	45	mΩ
Forward Transconductance	g fs	$V_{DS}=5V,I_{D}=4A$		10		S
DYNAMIC CHARACTERISTICS (Note4)						
Input Capacitance	C _{lss}			800		PF
Output Capacitance	C _{oss}	V _{DS} =8V,V _{GS} =0V, F=1.0MHz		155		PF
Reverse Transfer Capacitance	C _{rss}	1 - 1.00012		125		PF
SWITCHING CHARACTERISTICS (Note 4)						
Turn-on Delay Time	t _{d(on)}			18.3		nS
Turn-on Rise Time	tr	V_{DD} =10 V , I_{D} =1A		4.8		nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =4V, R_{GEN} =10 Ω		43.5		nS
Turn-Off Fall Time	t _f			20		nS
Total Gate Charge	Qg			11		nC
Gate-Source Charge	Q _{gs}	V _{DS} =10V,I _D =4A, V _{GS} =4V		2.2		nC
Gate-Drain Charge	Q _{gd}	v GS=4 v		2.5		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =2A		0.8	1.2	V
Diode Forward Current (Note 2)	I _S				2	Α



Test circuits and Waveforms



NOTES:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t \leq 10 sec.
- 3. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production testing.



SSF8205













Figure 2: Transfer Characteristics









5

SSF8205











Figure 10: Capacitance vs Vds











Figure 12: Normalized Maximum Transient Thermal Impedance



Mechanical Data:

SOT23-6

Dimensions in Millimeters (UNIT:mm)









SYMBOLS	MILLMETERS				
SIMBOLS	MIN.	NOM.	MAX.		
А			1.45		
A1			0.15		
A2	0.90	1.15	1.30		
b	0.30		0.50		
с	0.08		0.22		
D	2.90 BSC.				
E	2.80 BSC.				
E1	1.60 BSC.				
е	0.95 BSC.				
e1	1.90 BSC.				
L	0.30 0.45 0.60				
L1	0.60 REF				
L2	0.25 BSC.				
R	0.10				
R1	0.10 0.25				
θ	0 [.]	4	8.		
$\theta 1$	5	15			

NOTES:

- 1. All dimensions are in millimeters.
- 2. Dimensions are inclusive of plating
- 3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils.
- 4. Dimension L is measured in gauge plane.
- 5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



Ordering and Marking Information

Device Marking: 8205		
	Package (Available)	
	SOT23-6	
	Operating Temperature Range	
	C : -55 to 150 ⁰C	

Devices per Unit

Package	Units/	Tapes/	Units/	Inner Boxes/	Units/
Туре	Таре	Inner Box	Inner Box	Carton Box	Carton Box
SOT23-6	3000pcs	10pcs	30000pcs	4pcs	120000pcs

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	Tj=125℃ or 150℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			





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